

<b>Notice of References Cited</b>	Application/Control No. 10/577,147		Applicant(s)/Patent Under Reexamination FUKADA ET AL.	
	Examiner C. Aaron McIntyre		Art Unit 3621	Page 1 of 3

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	Examiner C. Aaron McIntyre		Art Unit 3621	Page 2 of 3

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	Examiner C. Aaron McIntyre		Art Unit 3621	Page 3 of 3

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	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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